

### FS16SM-VB Datasheet

## N-Channel 600V (D-S) Super Junction MOSFET

PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	650			
R <sub>DS(on)</sub> at 25 °C (Ω)	V <sub>GS</sub> = 10 V	0.38		
Q <sub>g</sub> max. (nC)	38			
Q <sub>gs</sub> (nC)	4			
Q <sub>gd</sub> (nC)	4.2			
Configuration	Single			

# **TO-3P** G

D (TAB)

#### **FEATURES**

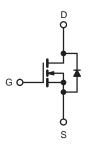




- Reduced switching and conduction losses
- Ultra low gate charge (Q<sub>a</sub>)
- Avalanche energy rated (UIS)

#### **APPLICATIONS**

- Server and telecom power supplies
- Switch mode power supplies (SMPS)
- Power factor correction power supplies (PFC)
- Lighting
  - High-intensity discharge (HID)
  - Fluorescent ballast lighting
- Industrial



N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATINGS</b> (T <sub>C</sub> = 25 °C, unless otherwise noted)						
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	600		
Gate-Source Voltage			$V_{GS}$	± 30	V	
Continuous Drain Current (T <sub>J</sub> = 150 °C)	\/ at 10.\/	$T_{\rm C} = 25  ^{\circ}{\rm C}$ $T_{\rm C} = 100  ^{\circ}{\rm C}$		11		
	V <sub>GS</sub> at 10 V	T <sub>C</sub> = 100 °C	I <sub>D</sub>	9.7	Α	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	50	I	
Linear Derating Factor				1.67/1.5/0.3	W/°C	
Single Pulse Avalanche Energy b			E <sub>AS</sub>	132	mJ	
Maximum Power Dissipation			$P_{D}$	83/83/31	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope	T <sub>J</sub> = 125 °C		-I) / /-I±	50		
Reverse Diode dV/dt <sup>d</sup>		dV/dt	3.1	V/ns		
Soldering Recommendations (Peak Temperature) <sup>c</sup>	for 10 s			300	°C	

- a. Repetitive rating; pulse width limited by maximum junction temperature. b.  $V_{DD}=50$  V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 4.5 A.
- c. 1.6 mm from case.
- d.  $I_{SD} \le I_D$ , dI/dt = 100 A/ $\mu$ s, starting  $T_J = 25$  °C.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-	60	°C/W	
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-	0.6	G/ VV	

PARAMETER	SYMBOL	TES	T CONDITIONS	MIN.	TYP.	MAX.	UNIT
Static		•					•
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		600	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I <sub>D</sub> = 1 mA		-	0.65	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$		-	4	٧
		$V_{GS} = \pm 20 \text{ V}$ $V_{GS} = \pm 30 \text{ V}$		-	-	± 100	nA
Gate-Source Leakage	I <sub>GSS</sub>			-	-	± 1	μΑ
		V <sub>DS</sub> =	V <sub>DS</sub> = 650 V, V <sub>GS</sub> = 0 V V <sub>DS</sub> = 520 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C		-	1	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>				-	10	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 5 A	-	0.38	-	Ω
Forward Transconductance	9fs	V <sub>DS</sub> = 30 V, I <sub>D</sub> = 5 A		-	16	-	S
Dynamic				•	•		
Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> = 0 V, V <sub>DS</sub> = 100 V, f = 1 MHz		-	680	-	pF
Output Capacitance	Coss			-	140	-	
Reverse Transfer Capacitance	C <sub>rss</sub>			-	5	_	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	V <sub>DS</sub> = 0 V to 520 V, V <sub>GS</sub> = 0 V		-	63	-	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	113	-	
Total Gate Charge	Qg			-	38	56	
Gate-Source Charge	Q <sub>gs</sub>	$V_{GS} = 10 \text{ V}$ $I_D = 5 \text{ A}, V_{DS} = 520 \text{ V}$		-	4	-	nC
Gate-Drain Charge	$Q_{gd}$			-	4.5	-	1
Turn-On Delay Time	t <sub>d(on)</sub>	$V_{DD} = 520 \text{ V}, I_D = 5 \text{ A}, V_{GS} = 10 \text{ V}, R_g = 9.1 \Omega$		-	13	25	ns
Rise Time	t <sub>r</sub>			-	11	35	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	81	90	
Fall Time	t <sub>f</sub>			-	25	40	
Gate Input Resistance	$R_{g}$	f = 1 MHz, open drain		-	3.5	-	Ω
<b>Drain-Source Body Diode Characteristic</b>	s						
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	11	
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	55	Α
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 5 A, V <sub>GS</sub> = 0 V		-	-	1.5	V
Reverse Recovery Time	t <sub>rr</sub>	T <sub>J</sub> = 25 °C, I <sub>F</sub> = I <sub>S</sub> = 5 A, dl/dt = 100 A/μs, V <sub>R</sub> = 400 V		-	270	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>			-	3.3	-	μC
Reverse Recovery Current	I <sub>RBM</sub>			_	30	_	A

#### Notes

- a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

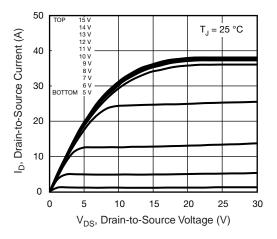


Fig. 1 - Typical Output Characteristics

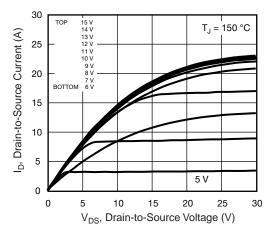


Fig. 2 - Typical Output Characteristics

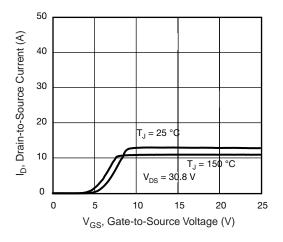


Fig. 3 - Typical Transfer Characteristics

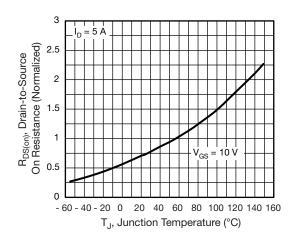


Fig. 4 - Normalized On-Resistance vs. Temperature

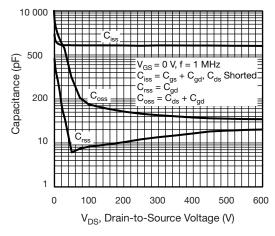


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

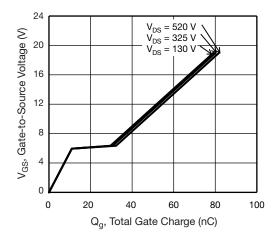


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage



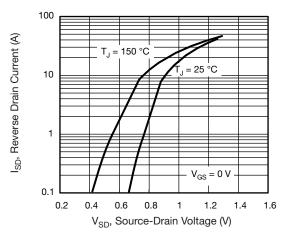


Fig. 7 - Typical Source-Drain Diode Forward Voltage

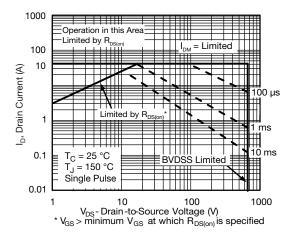


Fig. 8 - Maximum Safe Operating Area

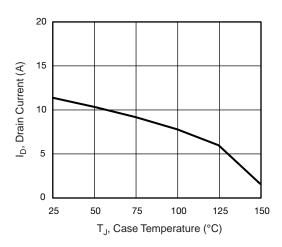


Fig. 9 - Maximum Drain Current vs. Case Temperature

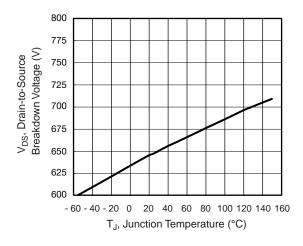


Fig. 10 - Temperature vs. Drain-to-Source Voltage

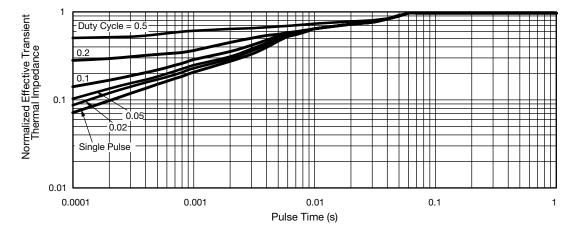


Fig. 11 - Normalized Thermal Transient Impedance, Junction-to-Case

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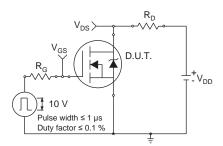


Fig. 12 - Switching Time Test Circuit

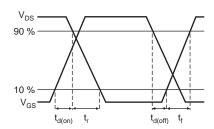


Fig. 13 - Switching Time Waveforms

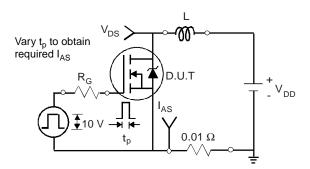


Fig. 14 - Unclamped Inductive Test Circuit

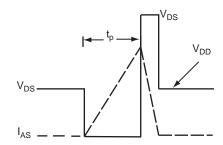


Fig. 15 - Unclamped Inductive Waveforms

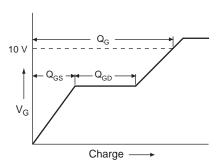


Fig. 16 - Basic Gate Charge Waveform

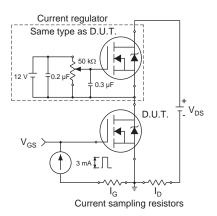
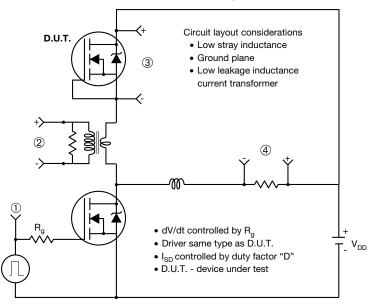


Fig. 17 - Gate Charge Test Circuit



### Peak Diode Recovery dV/dt Test Circuit



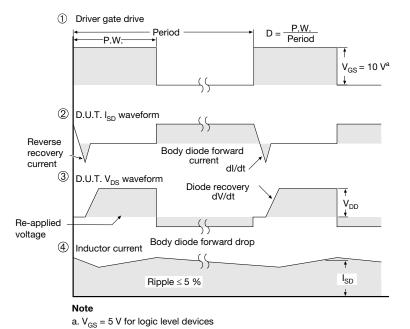
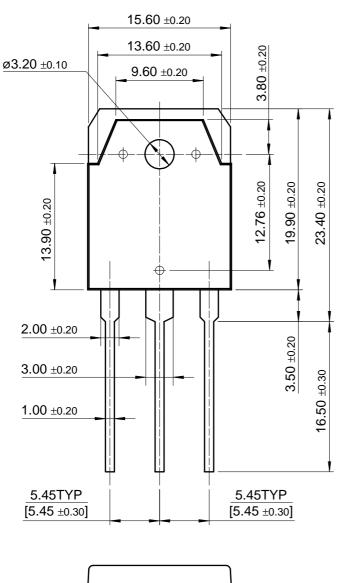


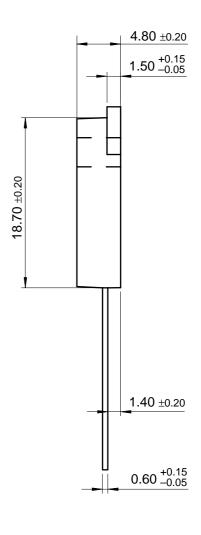
Fig. 18 - For N-Channel

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TO-3P







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